



RADIO TEST REPORT

Test Report No. : 27LE0315-HO-A-R1

Applicant : OMRON Corporation
Type of Equipment : Wireless Control Module
Model No. : G8D-645M
Test standard : FCC Part 15 Subpart C
Section 15.209: 2007
FCC ID : OUCG8D-645M
Test Result : Complied

1. This test report shall not be reproduced in full or partial, without the written approval of UL Japan, Inc.
2. The results in this report apply only to the sample tested.
3. This sample tested is in compliance with above regulation.
4. The test results in this report are traceable to the national or international standards.
5. Original test report number of this report is 27LE0315-HO-A.

Date of test:

August 8 to 22, 2007

Tested by:

T. Hatakeda

Takahiro Hatakeda
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Approved by :

M. Fujimura

Mitsuru Fujimura
EMC Services



NVLAP LAB CODE: 200572-0

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SECTION 1: Client information

Company Name : OMRON Corporation
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Contact Person : Masashi Matsuda

SECTION 2: Equipment under test (E.U.T.)

2.1 Identification of E.U.T.

Type of Equipment : Wireless Control Module
Model No. : G8D-645M
Sample No. : 9000
Country of Manufacture : Japan
Rating : DC12V
Receipt Date of Sample : August 3, 2007
Condition of EUT : Production prototype
(Not for Sale: This sample is equivalent to mass-produced items.)
Modification of EUT : No modification by the test lab.

2.2 Product Description

Model No: G8D-645M (referred to as the EUT in this report) is the Wireless Control Module.

Clock Frequency : 8MHz
Equipment Type : Transceiver

[Transmitter]
Frequency of Operation : 125kHz
Type of Modulation : ASK
Power Control : No
Antenna Type : Keycoil antenna
Operating Voltage (inner) : DC5.0V

[Receiver]
Receiving Frequency : 125kHz
Operating Voltage (inner) : DC5.0V

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SECTION 3: Test specification, procedures & results

3.1 Test Specification

Test Specification : FCC Part15 Subpart C: 2007
Title : FCC 47CFR Part15 Radio Frequency Device Subpart C Intentional Radiators
Section 15.207 Conducted Emission
Section 15.209 Radiated emission limits, general requirements

FCC 15.31 (e)

The power supply of the EUT is transformed to DC5.0V and the stable voltage DC5.0V is constantly provided to Radio part.

FCC Part 15.203 Antenna requirement

It is impossible for end users to replace the antenna, because the antenna is mounted inside of the EUT. Therefore, the equipment complies with the antenna requirement of Section 15.203.

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3.2 Procedures and results

No.	Item	Test Procedure	Specification	Remarks	Deviation	Worst margin *0)	Results
1	Conducted Emission	<FCC> ANSI C63.4:2003 7. AC powerline conducted emission measurements <IC> RSS-Gen 7.2.2	<FCC> Section 15.207 <IC> RSS-Gen 7.2.2	-	N/A *1)	N/A	N/A
2	Electric Field Strength of Fundamental Emission	<FCC> ANSI C63.4:2003 13. Measurement of intentional radiators <IC> RSS-Gen 4.8, 4.11	<FCC> Section 15.209 <IC> RSS-210 2.6, 2.7	Radiated	N/A	32.6dB 125.07kHz 0 deg. AV	Complied
3	Electric Field Strength of Spurious Emission	<FCC> ANSI C63.4:2003 13. Measurement of intentional radiators <IC> RSS-Gen 4.9, 4.11	<FCC> Section 15.209 <IC> RSS-210 2.6, 2.7	Radiated	N/A	16.3dB 73.545MHz, Vert., QP	Complied
4	-26dB Bandwidth	<FCC> ANSI C63.4:2003 13. Measurement of intentional radiators <IC> -	<FCC> Reference data <IC> -	Radiated	N/A	N/A	N/A

Note: UL Japan, Inc.'s EMI Work Procedures No.QPM05 and QPM15.

*0) The test result is round off to one or two decimal place, so some differences might be observed.

*1) The test is not applicable since the EUT is not the device that is designed to be connected to the public utility (AC) power line.

*These tests were performed without any deviations from test procedure except for additions or exclusions.

3.3 Addition to standards

No.	Item	Test Procedure	Specification	Remarks	Deviation	Worst margin	Results
1	99% Occupied Band Width	RSS-Gen 4.6.1	RSS-Gen 4.6.1	Radiated	N/A	N/A	N/A

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3.4 Uncertainty

The following uncertainties have been calculated to provide a confidence level of 95% using a coverage factor k=2.

Spurious Emission (Radiated)

The measurement uncertainty for this test using Loop antenna is $\pm 4.41\text{dB}(3\text{m}) / \pm 4.39\text{dB}(10\text{m})$.

The measurement uncertainty for this test using Biconical antenna is $\pm 4.59\text{dB}(3\text{m}) / \pm 4.58\text{dB}(10\text{m})$.

The measurement uncertainty for this test using Logperiodic antenna is $\pm 4.62\text{dB}(3\text{m}) / \pm 4.60\text{dB}(10\text{m})$.

The measurement uncertainty for this test using Horn antenna is $\pm 5.27\text{dB}$.

The data listed in this test report has enough margin, more than the site margin.

Other test except Conducted Emission and Spurious Emission (Radiated)

The measurement uncertainty for this test is $\pm 3.0\text{dB}$.

The data listed in this test report has enough margin, more than the site margin.

3.5 Test Location

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	FCC Registration Number	IC Registration Number	Width x Depth x Height (m)	Size of reference ground plane (m) / horizontal conducting plane	Other rooms
No.1 semi-anechoic chamber	313583	IC4247	19.2 x 11.2 x 7.7m	7.0 x 6.0m	No.1 Power source room
No.2 semi-anechoic chamber	655103	IC4247-2	7.5 x 5.8 x 5.2m	4.0 x 4.0m	-
No.3 semi-anechoic chamber	148738	IC4247-3	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.3 Preparation room
No.3 shielded room	-	-	4.0 x 6.0 x 2.7m	N/A	-
No.4 semi-anechoic chamber	134570	IC4247-4	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.4 Preparation room
No.4 shielded room	-	-	4.0 x 6.0 x 2.7m	N/A	-
No.5 semi-anechoic chamber	-	-	6.0 x 6.0 x 3.9m	6.0 x 6.0m	-
No.6 shielded room	-	-	4.0 x 4.5 x 2.7m	4.75 x 5.4 m	-
No.6 measurement room	-	-	4.75 x 5.4 x 3.0m	4.75 x 4.15 m	-
No.7 shielded room	-	-	4.7 x 7.5 x 2.7m	4.7 x 7.5m	-
No.8 measurement room	-	-	3.1 x 5.0 x 2.7m	N/A	-

* Size of vertical conducting plane (for Conducted Emission test) : 2.0 x 2.0m for No.1, No.2, No.3, and No.4 semi-anechoic chambers and No.3 and No.4 shielded rooms.

3.6 Test set up, Test instruments and Data of EMI

Refer to APPENDIX 1 to 3.

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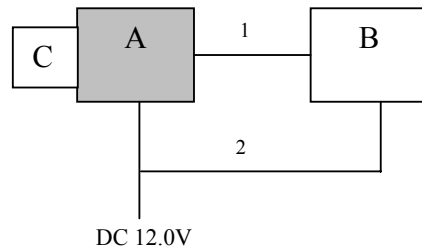
SECTION 4: Operation of E.U.T. during testing

4.1 Operating Modes

The mode is used : Transceiver 125kHz

Justification : The system was configured in typical fashion (as a customer would normally use it) for testing.

4.2 Configuration and peripherals



* Cabling and setup were taken into consideration and test data was taken under worse case conditions.

Description of EUT and Support equipment

No.	Item	Model number	Serial number	Manufacturer	Remarks
A	Wireless Control Module	G8D-645M	9000	OMRON	EUT
B	Dummy ECU	-	-	OMRON	-
C	Key	-	-	OMRON	-

List of cables used

No.	Name	Length (m)	Shield	
			Cable	Connector
1	Signal Cable	1.4	Unshielded	Unshielded
2	DC Cable	1.4	Unshielded	Unshielded

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SECTION 5: Radiated emission (Fundamental and Spurious Emission and –26dB Bandwidth)

Test Procedure

The Radiated Electric Field Strength intensity has been measured on No. 2 and 3 semi anechoic chamber with a ground plane and at a distance of 3m.

Frequency : From 9kHz to 30MHz at distance 3m

The EUT was rotated a full revolution in order to obtain the maximum value of the electric field intensity.

The measurements were performed for each antenna angle 0deg. , 45deg. and 90deg.

Frequency : From 30MHz to 1GHz at distance 3m

The measuring antenna height varied between 1 and 4m and EUT was rotated a full revolution in order to obtain the maximum value of the electric field intensity.

The measurements were performed for both vertical and horizontal antenna polarization.

Measurements were performed with a QP, PK, and AV detector.

The radiated emission measurements were made with the following detector function of the test receiver (below 1GHz).

	From 9kHz to 90kHz and From 110kHz to 150kHz	From 90kHz to 110kHz	From 150kHz to 490kHz	From 490kHz to 30MHz	From 30MHz to 1GHz
Detector Type	PK/AV	QP	PK/AV	QP	QP
IF Bandwidth	200Hz	200Hz	9kHz	9kHz	120kHz

- The carrier level (or, noise levels) was (or were) measured at each position of all three axes X, Y and Z, and the position that has the maximum noise was determined.

With the position, the noise levels of all the frequencies were measured.

* Part 15 Section 15.31 (f)(2) (9kHz-30MHz)

[Limit at 3m]=[Limit at 300m]-40 x log (3[m]/300[m])

[Limit at 3m]=[Limit at 30m]-40 x log (3[m]/30[m])

Test data : **APPENDIX 3**

Test result : **Pass**

Date: August 8 to 22, 2007

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